US00D780695S

(12) **United States Design Patent** (10) **Patent No.: US D780,695 S**
**Tosto et al.** (45) **Date of Patent: ** Mar. 7, 2017**

---

(54) **MODULAR PROBE**

(71) Applicant: **General Electric Company**, Schenectady, NY (US)

(72) Inventors: **Ryan Walter Tosto**, Boalsburg, PA (US); **Jean-Francois Bureau**, St-Jerome (CA); **Jeffrey Bishop Draper**, McVeytown, PA (US)

(73) Assignee: **General Electric Company**, Schenectady, NY (US)

(**) Term: **15 Years**

(21) Appl. No.: **29/529,932**

(22) Filed: **Jun. 11, 2015**

### Related U.S. Application Data

(63) Continuation of application No. 29/484,162, filed on Mar. 6, 2014, now Pat. No. Des. 734,271.

(51) **LOC (10) Cl.** ............................................... **13-03**

(52) **U.S. Cl.**
USPC ......................................................... **D13/147**

(58) **Field of Classification Search**
USPC ...... D13/101, 110, 118, 123, 133, 146, 147, D13/154, 184, 199; 307/150, 152; 361/600, 601, 622, 730, 796, 809; 439/62, 79, 260, 329, 395, 422, 499
CPC ................................ H01R 12/79; H01R 12/88
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

| | | | | | |
|---|---|---|---|---|---|
| 4,913,656 | A | | 4/1990 | Gordon et al. | |
| 5,577,936 | A | * | 11/1996 | Hahn | H01R 23/6873<br>439/607.28 |
| D409,981 | S | * | 5/1999 | Wu | D13/147 |
| D411,174 | S | | 6/1999 | Huang | |
| D412,884 | S | * | 8/1999 | Wu | D13/147 |
| D414,161 | S | | 9/1999 | Huang | |
| D414,467 | S | | 9/1999 | Aizawa et al. | |
| D421,420 | S | * | 3/2000 | Wu | D13/147 |
| 6,224,418 | B1 | | 5/2001 | Miura et al. | |
| D470,112 | S | | 2/2003 | Kato et al. | |
| D471,873 | S | * | 3/2003 | Kawase | D13/147 |
| D478,319 | S | | 8/2003 | Yeh | |
| 6,790,074 | B1 | | 9/2004 | Chiu | |
| D518,788 | S | | 4/2006 | Fan | |
| D519,083 | S | | 4/2006 | Li et al. | |
| D539,747 | S | | 4/2007 | Igarashi et al. | |
| D595,231 | S | | 6/2009 | Xu et al. | |
| D627,738 | S | | 11/2010 | Luo | |
| D628,159 | S | | 11/2010 | Inomae | |
| D636,737 | S | | 4/2011 | Ngo et al. | |
| D637,956 | S | | 5/2011 | Yuan et al. | |
| D680,959 | S | | 4/2013 | Katayanagi | |
| D699,682 | S | | 2/2014 | Yokoyama | |

(Continued)

*Primary Examiner* — Derrick Holland
*Assistant Examiner* — Jennifer O King
(74) *Attorney, Agent, or Firm* — Barclay Damon, LLP

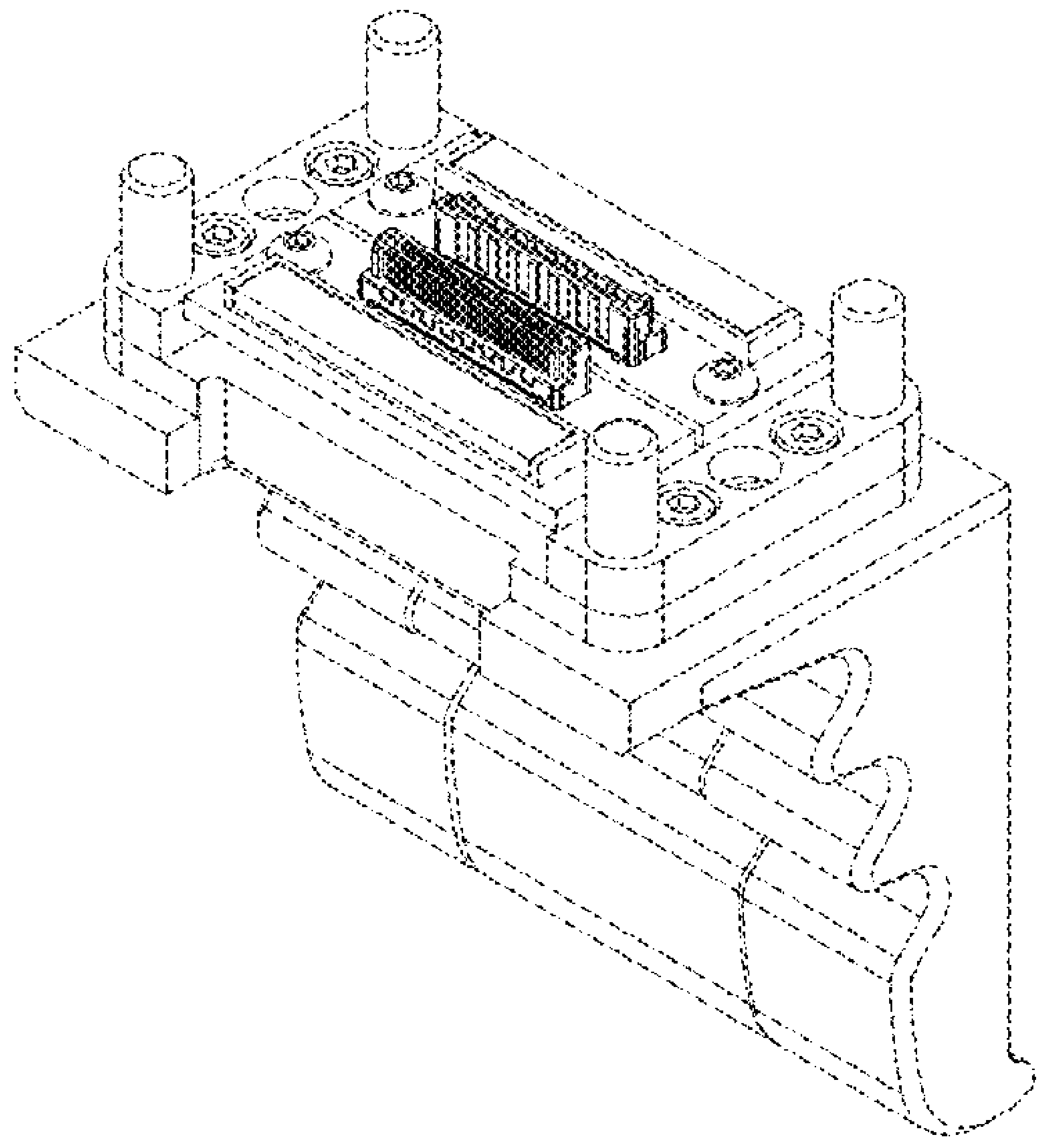
(57) **CLAIM**

The ornamental design for a modular probe, as shown and described.

### DESCRIPTION

FIG. **1** is a perspective view of a modular probe showing our new design;
FIG. **2** is a front elevation thereof;
FIG. **3** is a right elevation thereof;
FIG. **4** is a top plan view thereof;
FIG. **5** is a back elevation thereof; and,
FIG. **6** is a left elevation thereof.
The broken lines shown represent unclaimed subject matter and form no part of the claimed design.

**1 Claim, 6 Drawing Sheets**



## (56) References Cited

U.S. PATENT DOCUMENTS

| | | | |
|---|---|---|---|
| D703,615 | S | 4/2014 | Takenaga et al. |
| D706,723 | S | 6/2014 | Yokoyama |

* cited by examiner

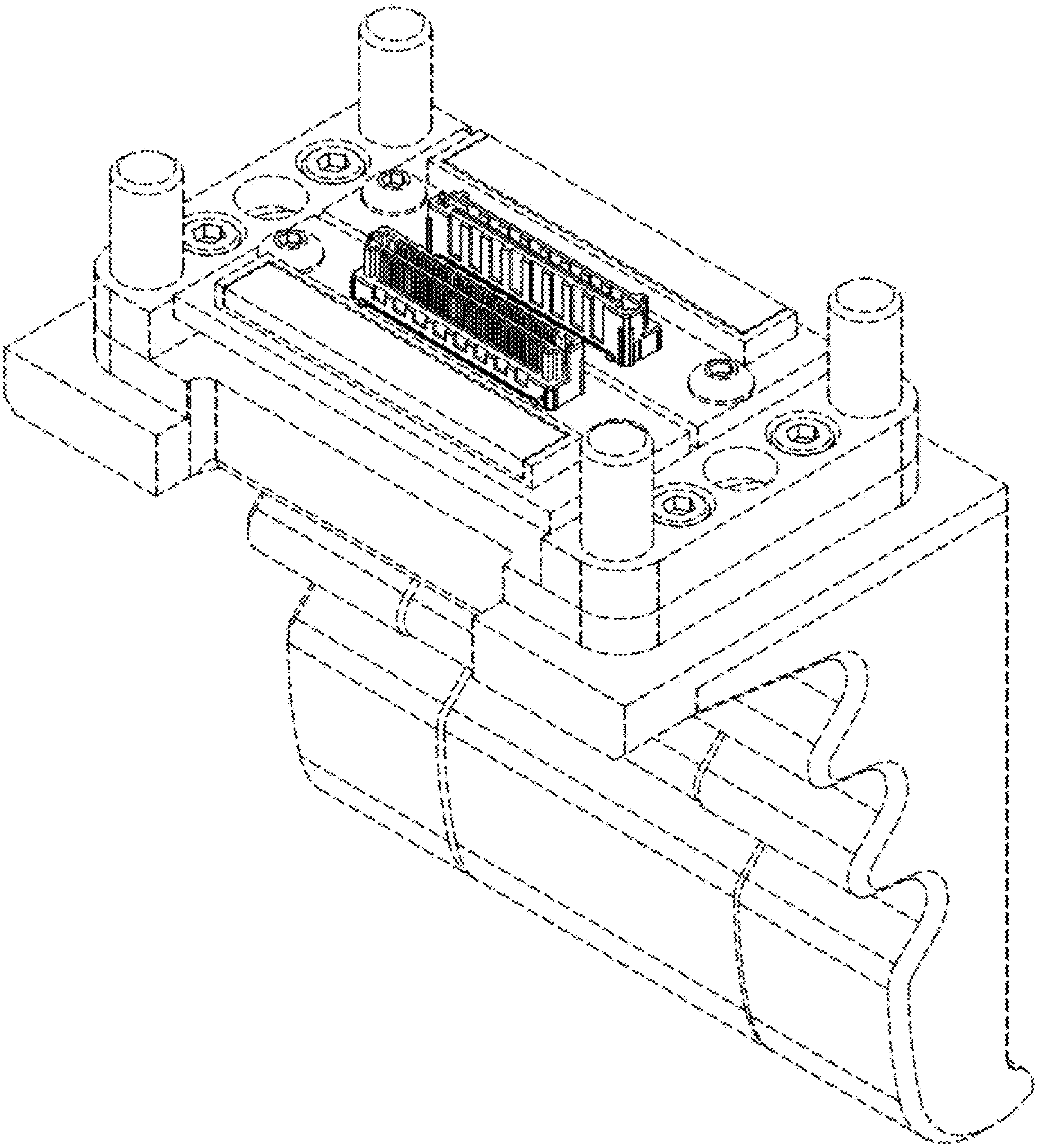


FIG. 1

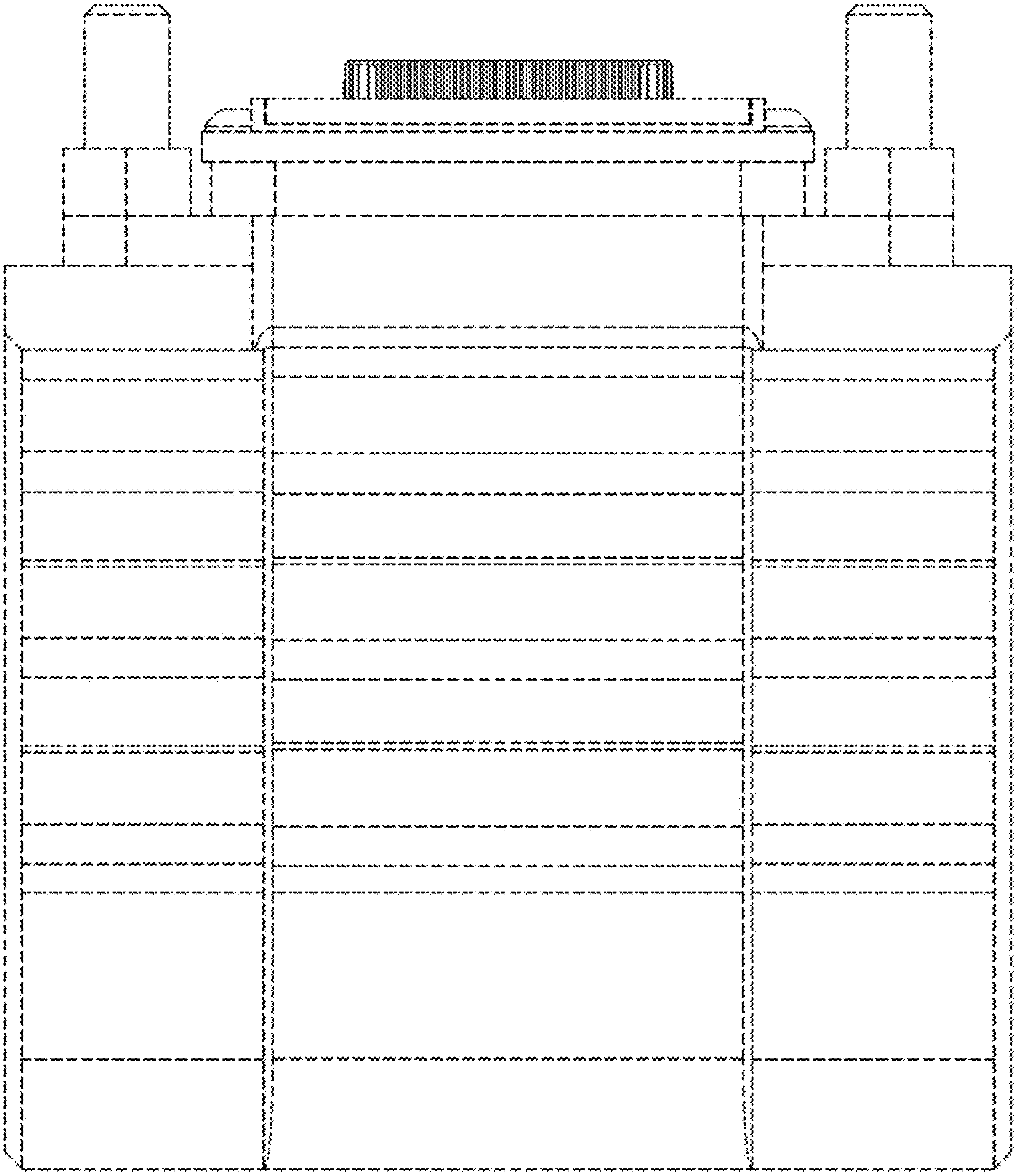


FIG.2

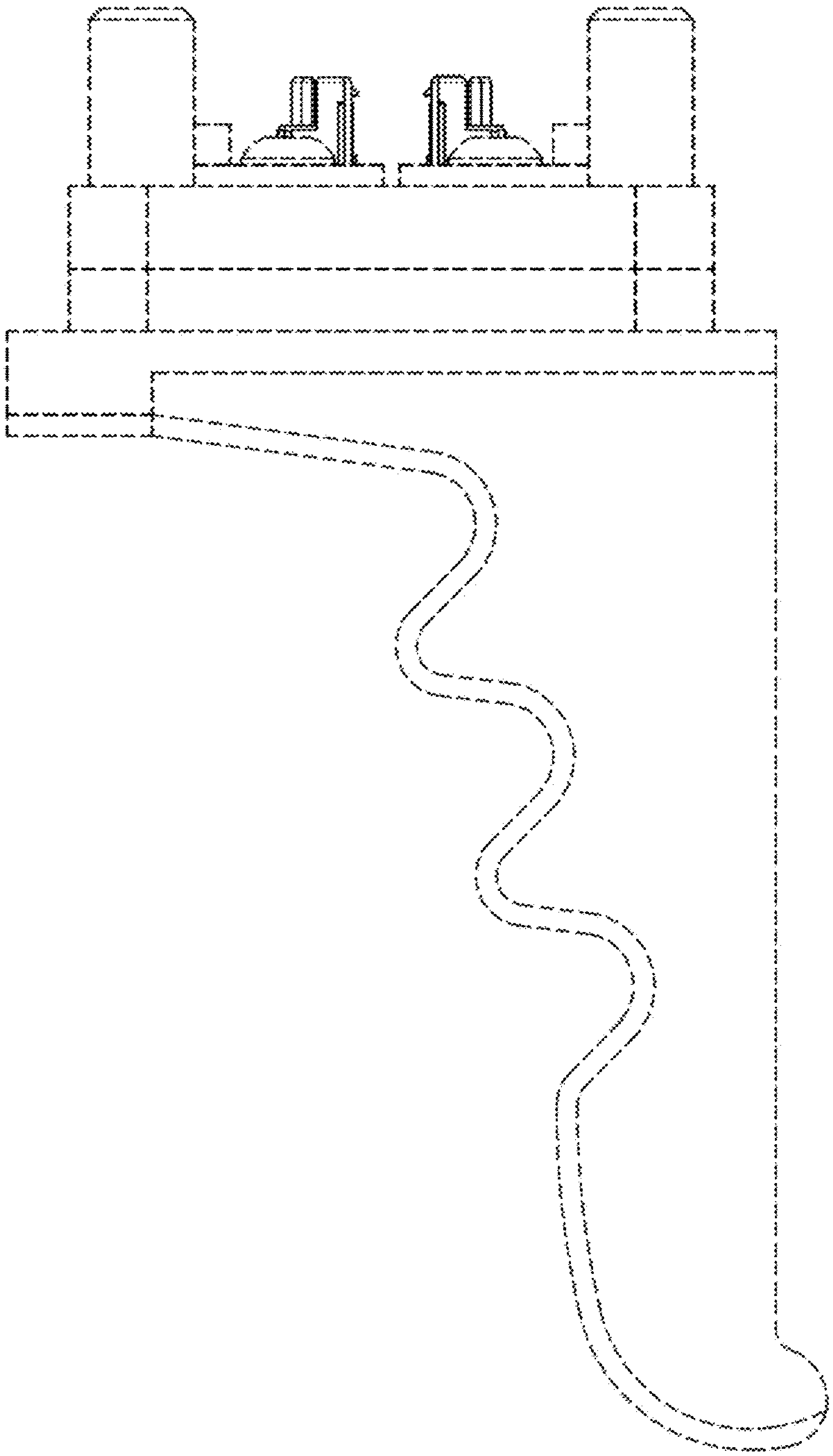


FIG.3

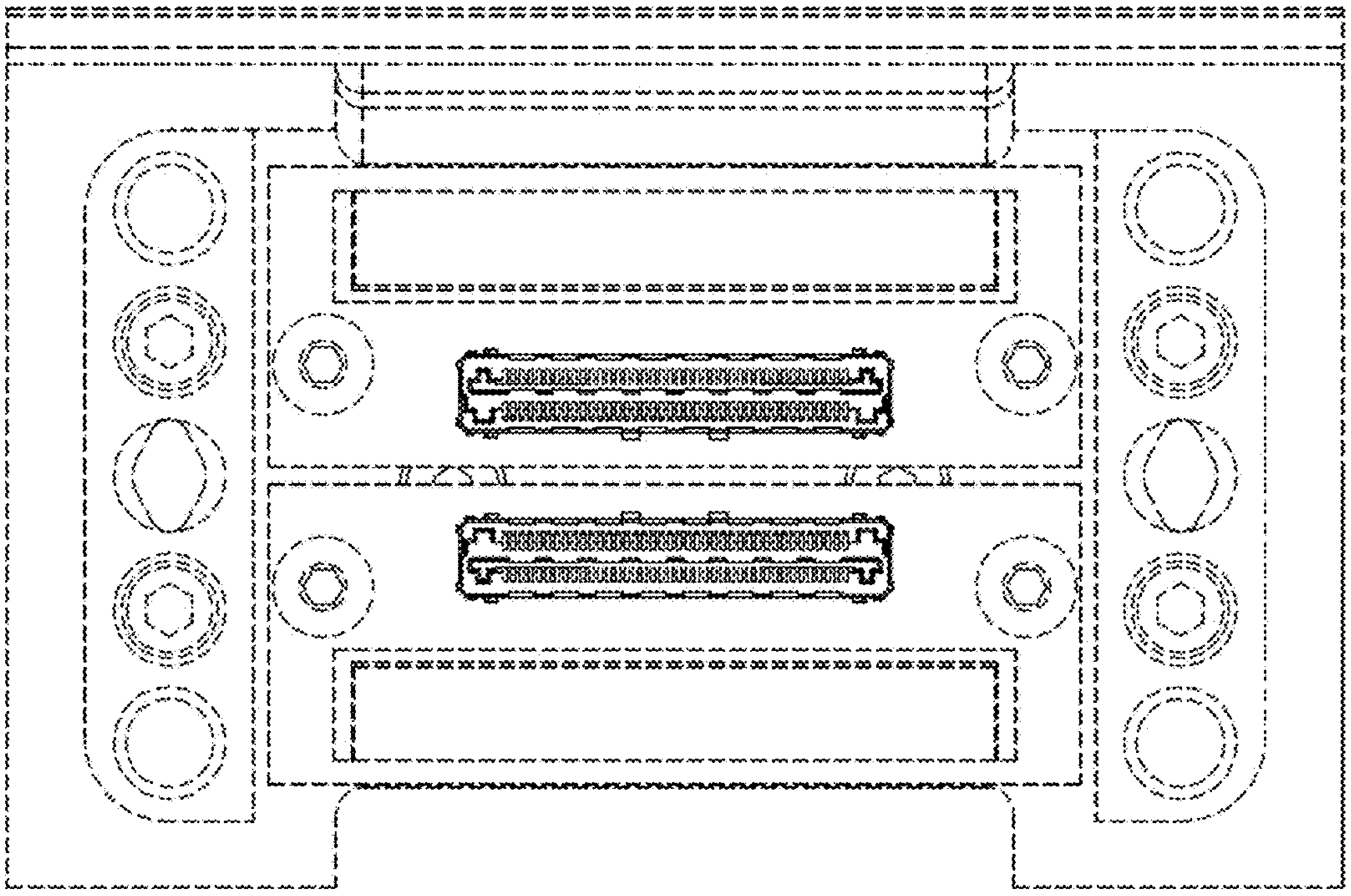


FIG.4

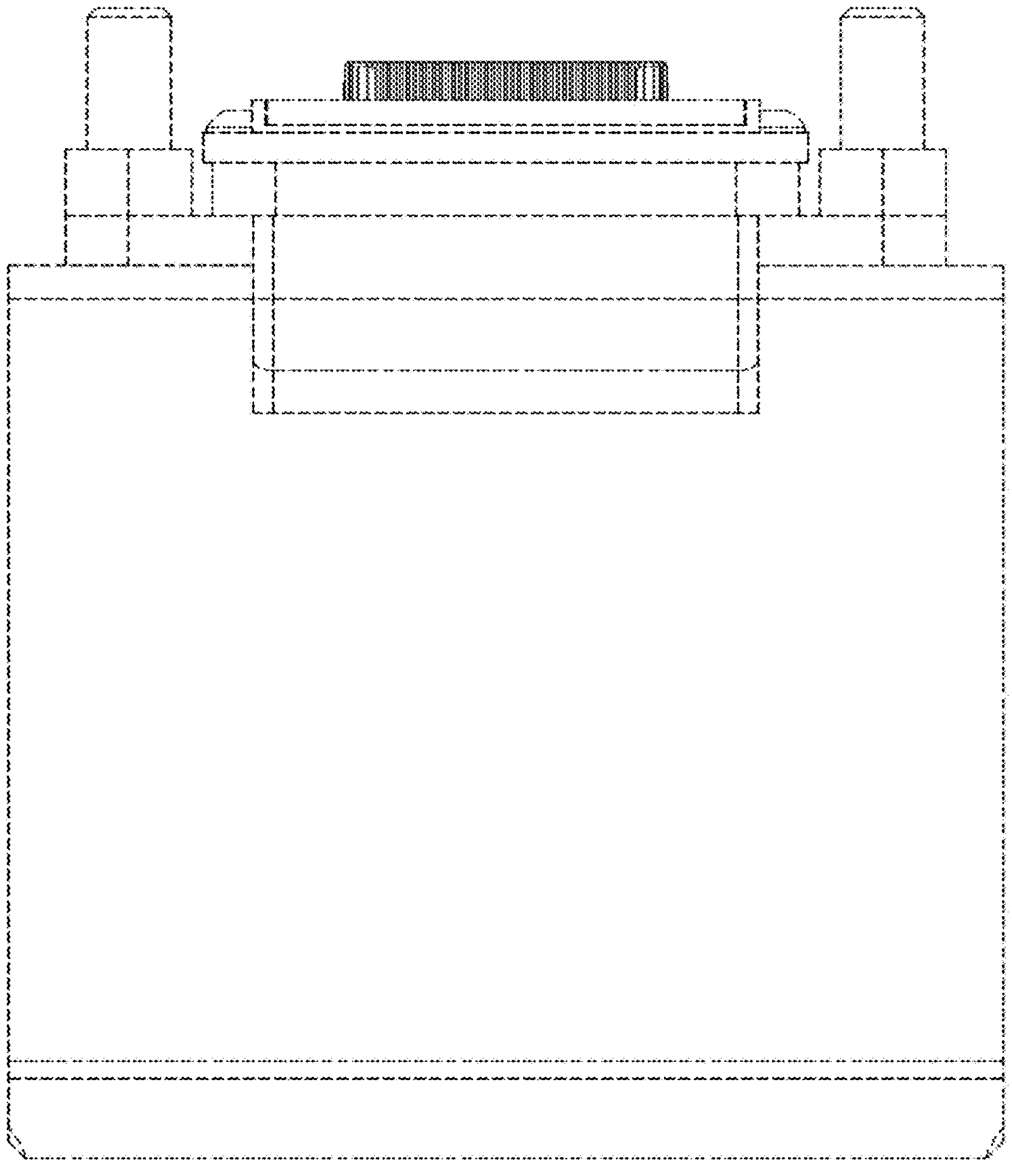


FIG.5

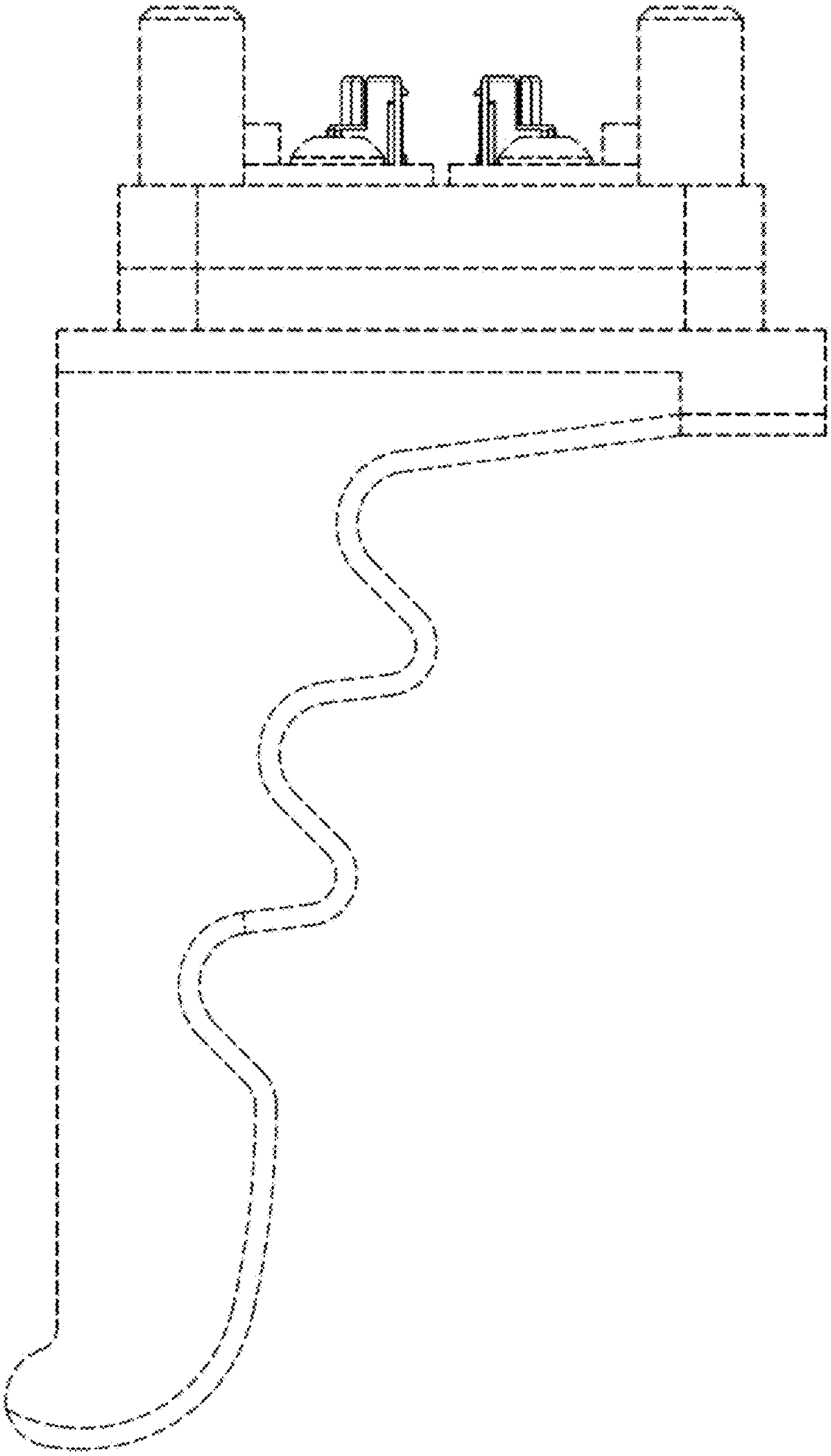


FIG. 6